Docket No.

215930US99

#### TATES PATENT AND TRADEMARK OFFICE IN THE

IN RE APPLICATION OF:

DIRK C. JORDAN ET AL

SERIAL NO: 09/986,899

GAU:

FILED: FOR:

**NOVEMBER 13, 2001** 

EXAMINER: WILLE

STRUCTURE AND METHOD FOR FABRICATING SEMICONDUCTOR STRUCTURES AND DEVICES

UTILIZING THE FORMATION OF A COMPLIANT SUBSTRATE HAVING A NIOBIUM CONCENTRATION

# INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

Applicant(s) wish to disclose the following information.

# REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

# RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

# **CERTIFICATION**

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

# **DEPOSIT ACCOUNT**

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

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ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 215930US99 09/986,899 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Dirk C. JORDAN, et al. FILING DATE **GROUP** November 13, 2001 2814 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB **FILING DATE** DATE **CLASS** NAME INITIAL NUMBER **CLASS** IF APPROPRIATE UT 5,528,209 06/18/96 Macdonald et al. UΥ 12/07/99 5,998,781 Vawter et al. UW 6,110,813 08/29/00 Ota et al. UX 09/17/02 6,452,232 B1 Adan UY 6,049,110 04/11/00 Koh UΖ 5,559,368 09/24/96 Hu et al. VΑ 6,392,253 B1 05/21/02 Saxena VΒ 5,585,288 12/17/96 Davis et al. VC 12/07/93 5,268,327 Vernon VD 6,198,119 B1 03/06/01 Nabatame et al. VΕ 6,113,225 09/05/00 Miyata et al. VF 11/16/93 Grudkowski et al. 5,262,659 ۷G 6,239,012 B1 05/29/01 Kinsman VΗ 6,297,598 10/02/01 Wang et al. VΙ 2002/140012 10/03/02 Droopad VJ 4,866,489 09/12/89 Yokogawa et al. VΚ 6,080,378 06/27/00 Yokota et al. VL 5,508,554 04/16/96 Takatani et al. VM 6,477,285 B1 11/05/02 Shanley VN 4,695,120 09/22/87 Holder VO 03/16/99 5,882,948 Jewell VΡ 5,574,589 11/12/96 Feuer et al. VQ 5,510,665 04/23/96 Conley VR 4,804,866 02/14/89 Akiyama vs 5,057,694 10/15/91 Idaka et al. VT 06/03/97 Pique et al. 5,635,453 VU 5,719,417 02/17/98 Roeder et al. W 5.998.819 12/07/99 Yokoyama et al.

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner

**Date Considered** 

5 ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 215930US99 09/986,899 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Dirk C. JORDAN, et al. **GROUP** FILING DATE 2814 November 13, 2001 **U.S. PATENT DOCUMENTS** SUB **FILING DATE EXAMINER** DOCUMENT DATE NAME **CLASS** IF APPROPRIATE **CLASS** NUMBER INITIAL 2002/0079576 06/27/02 Seshan VW ٧X 5,148,504 09/15/92 Levi et al. 12/26/02 Klosowiak VY 2002/0195610 A1 Matsuda 12/19/95 ٧Z 5,477,363 05/18/99 Butler et al. WA 5,905,571 5,570,226 10/29/96 Ota WB Ishibashi et al. WC 5,087,829 02/11/92 09/06/01 Saito WD 2001/0020278 A1 Uchizaki 6,496,469 B1 12/17/02 WE Doi et al. 10/21/97 WF 5,679,947 WG 2001/0036142 A1 11/01/01 Kadowaki et al. 08/29/95 Yoshida et al. WH 5,446,719 WI 5,831,960 11/03/98 Jiang et al. McKee et al. 12/02/97 WJ 5,693,140 04/23/02 Wang et al. WK 6,376,337 B1 WL 4,177,094 12/04/79 Kroon Makki et al. 06/01/93 WM 5,216,359 Nashimoto et al. 10/23/01 WN 6,307,996 B1 12/06/94 Stevens wo 5,371,621 Bojarczuk, Jr et al. 2002/0145168 A1 10/10/02 WP 11/02/71 Anderson WQ 3,617,951 11/17/98 Bevan et al. WR 5,838,053 11/04/97 Wersing et al. 5,684,302 WS Shichijo et al. WT 5,959,308 09/28/99 11/08/94 Yazawa et al.

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LIST OF REFERENCES CITED BY APPLICANT

Dirk C. JORDAN, et al.

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